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BSc in Micro and Nanotechnology Engineering

# Solution-processed oxide thin films for electrochromic devices application

MASTER IN Micro and Nanotechnology Engineering

NOVA University Lisbon

September, 2024





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## ACKNOWLEDGMENTS

Firstly, i express my gratefulness to the institution that embraced me for the last five years, NOVA School of Science and Technology, especially to the Department of Material Sciences. Secondly, a special thank you to my supervisors Dr. Rita Branquinho and Dr. Emanuel Carlos, for their incredible patience to guide me. Their knowledge and guidance were essential to complete this challenging work.

To the people of CENIMAT and CEMOP, who provided me with the formations to use the equipment and helped me every time i asked.

I cannot put into words how thankful i am to all the teachers that were part of my life, from the first cycle to the university, from the ones who taught me how to read to the ones who introduced me to nanotechnologies, learning was always a big pleasure of mine and i look forward continuing to do it. A particular thank you to Mrs. Mirna, who taught me everything i know about the English language, i could not have written this document without those years of intensive learning.

Another big thank you to my friends, they were always there ready to share a laugh and have always helped me to relax during stressful moments.

Finally, a warm thank you to my family, they have always provided me everything i needed to finish my studies. A special thank you to my grandfather, whose company and great abilities to grill fish were essential to give me the final confidence and energy to finish this work.

This work was financed by national funds from FCT - Fundação para a Ciência e a Tecnologia, I.P., in the scope of the projects LA/P/0037/2020, UIDP/50025/2020 and UIDB/50025/2020 of the Associate Laboratory Institute of Nanostructures, Nanomodelling and Nanofabrication – i3N).



" So, to work now! Lift up your hammers!"  
Giuseppe Verdi, in "Il Trovatore"



## ABSTRACT

Electrochromic (EC) devices allow to reversibly change their colour when a small voltage is applied and can be used in buildings, satellites or airplanes. NiO and WO<sub>3</sub> are two promising electrochromic materials with great electrochromic properties. Once NiO is a cathodic and WO<sub>3</sub> is an anodic EC material, it is beneficial to combine them in a complementary effect electrochromic window. The production techniques of both NiO and WO<sub>3</sub> devices have been evolving but are still expensive due to typical vacuum-based and high pressure production processes. Therefore, it is highly important to find new low-cost methods that can allow to produce EC films with good electrochromic properties. Solution combustion synthesis (SCS) is a simple low-cost method and a possible alternative. In this work, NiO and WO<sub>3</sub> films were produced through SCS and deposited by spin coating. Once the film production was optimized, they were structurally, optically and electrochemically characterized. NiO and WO<sub>3</sub> films presented a thickness of (195±6) nm and of (53±3) nm, respectively. Both films did not present long range order and only NiO films presented a porous structure. WO<sub>3</sub> and NiO films presented an identical optical modulation of 20%. Cyclic voltammetry measures revealed two oxidation and two reduction peaks for NiO films and only one reduction peak for WO<sub>3</sub>. Finally, NiO and WO<sub>3</sub> films presented low operating voltages and coloration/bleaching times of (21±1)/(8±1) s and (45±7)/(46±4) s, respectively. The films exhibited a promising reversible electrochromic behaviour which can be employed in complementary effect electrochromic windows after process optimization.

**Keywords:** Electrochromic, Nickel Oxide, Tungsten Oxide, Spin Coating, Solution Combustion Synthesis.



## RESUMO

Os dispositivos electrocrómicos mudam reversivelmente de cor quando uma pequena tensão é aplicada nos seus terminais, podendo ser usados em edifícios, satélites ou aviões. NiO e WO<sub>3</sub> são dois materiais electrocrómicos promissores que sendo, respetivamente, catódico e anódico, podem ser combinados numa janela electrocrómica de efeito complementar. Os métodos de fabrico de dispositivos à base destes materiais têm vindo a evoluir, mas como ainda assentam em processos de vácuo e altas pressões, permanecem os altos custos de produção. Assim, torna-se importante encontrar métodos *low-cost* que permitam produzir dispositivos com boas propriedades electrocrómicas. A síntese por combustão (SCS) apresenta-se como um método simples e de baixo custo. Neste trabalho filmes de NiO e WO<sub>3</sub> foram produzidos por SCS e depositados por spin coating. Após otimização do processo de fabrico, os filmes foram estruturalmente, opticamente e electroquimicamente caracterizados. Os filmes de NiO apresentaram uma espessura de (195±6) nm e os de WO<sub>3</sub> de (53±3) nm. Os filmes não apresentaram ordem a longas distâncias e apenas os filmes de NiO apresentaram uma estrutura porosa. Os filmes de WO<sub>3</sub> e de NiO apresentaram uma modulação ótica semelhante, de cerca de 20%. As medidas de volumetria cíclica revelaram a presença de dois picos de redução e dois picos de oxidação para os filmes de NiO, mas apenas um pico de redução foi registado para o filme de WO<sub>3</sub>. Por fim, os filmes de NiO apresentaram tempos de coloração/ descoloração de (21±1)/(8±1) s e os de WO<sub>3</sub> (45±7)/ (46±4) s. Desta forma tanto os filmes de NiO como os de WO<sub>3</sub> exibiram um comportamento electrocrómico reversível, podendo ser usados em janelas electrocrómicas após otimização do processo de fabrico.

**Palavas chave:** eletrocromismo, Óxido de Níquel, Óxido de Tungsténio, Spin Coating, Síntese por Combustão



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## GLOSSARY

<b>Electrochrom- ism</b>	A phenomenon in which a material displays changes in colour or transparency
<b>Transmittance</b>	Ratio of the light energy falling on a body to that transmitted through it
<b>Optical Modu- lation</b>	Difference of transmittance between coloured and bleaching states



## ACRONYMS

EC	Electrochromic device
ISL	Ion Storage Layer
ECL	Electrochromic Layer
TMOs	Transition Metal Oxides
SCS	Solution combustion Synthesis
ITO	Indium thin oxide
FTO	Fluorine doped thin oxide
CE	Coloration efficiency
FTIR-ATR	Fourier Transform Infrared Total Reflectance-Attenuated Total Reflectance
SEM	Scanning Electron Microscopy
XRD	X Ray Diffraction
IPCC	International Panel on Climate Change
OV	Oxidising Valence
RV	Reducing Valence



## SYMBOLS

$\Phi$	Reducer/oxidizer ratio
$t_{c\ 90\%}$	Coloration time
$t_{b\ 90\%}$	Bleaching time
$\Delta T$	Optical modulation

## MOTIVATION

One of the biggest challenges of the 21<sup>st</sup> century is the threat of climate change. According to the Intergovernmental Panel on Climate Change (IPCC), global warming may lead to an increase of earth's average temperature 1.5 °C above pre-industrial levels [1]. One of the challenges science must address is the thermal isolation of buildings, since they consume a large portion of the total energy that is produced. Around 30% of a building's energy is lost by windows, therefore it is necessary to find new technologies that can help mitigate this energy loss [2]. Electrochromic devices are promising candidates, since they are designed to reversibly change their transmittance and colour when a small voltage is applied, they take less energy consumption. There are a wide variety of applications where they can be employed like information displays, thermal control of satellites and smart windows, leading to more energy efficient buildings, satellites or even airplanes. The main objective of this work is to produce NiO and WO<sub>3</sub> thin films by solution combustion synthesis and to study their electrochromic behaviour and application in electrochromic devices.



Figure i- Electrochromic Window produced by Wglass

## INTRODUCTION

The first reports of electrochromism were published in 1953 at the Blazers AZ, where colour changes were observed when immersing  $\text{WO}_3$  films in sulfuric acid [3]. In 1969 *Deb* created the first electrochromic (EC) device using  $\text{WO}_3$ , but during the second half of the 1970s, liquid crystals started to dominate the market [3]. Later, in 1980, the energy efficiency of EC devices highlighted their potential and new developments were made in the field, at the same time NiO EC films started to be developed [3]. The evolution continued and these devices are now widely present on the market and can be seen in diverse applications such as airplanes, buildings and satellites [4].

### 1.1 Structure and materials of EC devices

Figure 1.1 presents the basic configuration of an EC device: substrate/transparent conductor/ EC film/ electrolyte/ counter electrode. In order to achieve colouration, an electrical field is applied between the counter electrode and the transparent conductor, leading to the oxidation/reduction of the EC film through the insertion/extraction of ions from the electrolyte, changing its optical bandgap and consequently its colour [5]. Cathodic EC materials achieve coloration through ion insertion (electrochemical reduction), while anodic EC materials through ion extraction (electrochemical oxidation)[6].

For real life applications, EC films are, often, incorporated in a 5 layer EC device where the counter electrode is an ion storage layer (ISL), also deposited over a transparent conductor and a substrate [5]. The ISL can also consist of an EC film, in this case the removal of electrons from the ISL layer will change its colour. Once both ISL and ECL will change their colour, there is colour overlay, this phenomenon is called complementary effect [4].

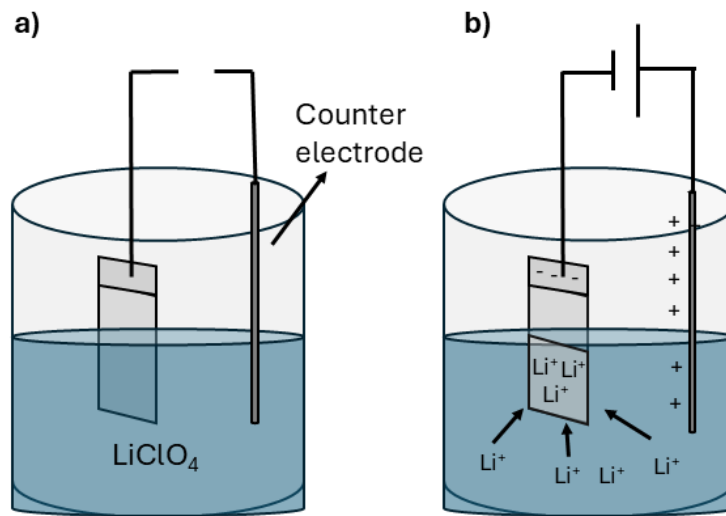


Figure 1.1- EC mechanism of a cathodic Electrochromic film with a) no voltage applied b) a voltage applied

Transparent conductors allow insertion/extraction of charges into the device and are usually tin doped indium oxide (ITO) or fluorine doped tin oxide (FTO) [4].

The performance on an EC film vastly depends on the electrolyte. Its main function is as source of ionic species and to allow ionic conductivity. Therefore, the performance will depend on the size, volume and diffusion kinetics of the electrolyte ions [7].  $\text{Li}^+$  based electrolytes are widely used due to their fast diffusion assured by the small ionic radius of Li ions, but still remain expensive, unsafe and rely on a critical raw material [7]. Non-metal  $\text{H}^+$  have an even smaller ionic radius, with faster diffusion times, yet corrosion and hydrogen leakage have led to poor durability and unstable performance of the devices [7]. Electrolytes based on  $\text{Na}^+$  and  $\text{K}^+$  ions have emerged due to their safety and abundance, but their large ionic radius does not make them attractive for EC device fabrication [7]. Multi valent ion based electrolytes (like  $\text{Zn}^{2+}$ ,  $\text{Ca}^{2+}$ ,  $\text{Al}^{3+}$ ,  $\text{Mg}^{2+}$ ) are another alternative that takes advantage of the multiple ions that can be involved in the reaction, increasing the switching speed of a device, however strong electrostatic interactions between the inserted ions and the host materials lead to poor cyclic stability and low optical contrast, therefore it is not a popular alternative [7].

To evaluate the EC performance of a device it is important to consider several parameters, such as optical modulation, switching time and coloration efficiency[6]. Optical modulation refers to the difference of transmittance in coloured and bleached states [6]. Switching Time evaluates the time needed to switch from coloured to bleached state and from bleached to colour state, usually it is measured when there is an optical change of 90%[6]. Coloration efficiency (CE) helps understanding the efficiency of the colouring/bleaching process and is defined as the optical modulation per injected charge per unit area [6]. To assure fast switching times both

the electrolyte and the EC film should have high ionic conductivity [4]. The EC film must also present high electronic conductivity, large optical transmittance, high coloration efficiency and cyclic durability[4].

The performance of an EC device depends on several factors like the EC film surface area, crystallinity, electrical conductivity, porosity and roughness [2], [8]. One of the main parameters that has a great influence on the EC properties is the surface area. Higher surface areas increase the space available for ion-film reactions, decreasing the diffusion length of the electrolyte ions and, consequently decreasing coloration/bleaching times [6]. Crystallinity has a strong influence on the surface area of the films. Amorphous films tend to have more surface area available than crystalline films due to the lack of long range order, improving ion insertion/extraction and increasing the switching speed [8]. On the other hand, crystalline films have better adhesion to the substrate and are more stable [8]. The porosity of the films and the existence of microstructures are other factors that can increase the surface area, enhancing the performance of the device[2], [8].

Several materials have been used to produce EC films, but transition metal oxides (TMOs) have become a popular choice due to their high chemical stability, high electrochemical activity and appropriate potential window [2].

NiO has been widely used as an anodic metal oxide due to its compatibility with EC windows, low-cost and ease of preparation, but their low conductivity, optical modulation and life cycle are still drawbacks that need to be addressed [2]. Among the several techniques (sputtering, sol gel, hydrothermal, solvothermal, spin coating ) that have been reported ,(table 1.1), NiO films produced by hydrothermal synthesis have shown good results with high optical modulation, 70 % (600 nm), good cycling stability, and small coloration/bleaching times, 5/7s [9], [10], [11], [12], [13]. Although hydrothermal synthesis may allow to produce films with microstructures, its high pressure and high temperature requirements are not attractive for large scale production [2].

WO<sub>3</sub> has become a promising cathodic metal oxide due to its high optical modulation, high colouring efficiency, short switching times and low cost [8]. However, its cycling stability is still insufficient for some applications and expensive techniques like solvothermal and sputtering continue to dominate its fabrication method [8]. As shown in table 1.1, hydrothermal, self-assembly, spray coating, vacuum evaporation and APCVD are among several techniques reported to produce WO<sub>3</sub> EC films, [14], [15], [16], [17], [18]. There are reports of sputtering made WO<sub>3</sub> films with controllable crystallinity, high optical modulations, 73 % (1000 nm), small coloured/bleaching times, 5/3 s, and high CE, 81 Cm<sup>2</sup>.C<sup>-1</sup> [19]. *Y.Yao* reported WO<sub>3</sub> crystalline

quantum dots made by spray coating with high optical modulation, 98% (633 nm), fast coloration/bleaching times, 5/4 s, high CE of  $77 \text{ Cm}^2.\text{C}^{-1}$  and excellent cycling stability (3000 cycles with 10% optical loss) [18]. The mass production of both NiO and  $\text{WO}_3$  still rely on high-cost methods, therefore it is important to study a low-cost production technology that can allow to produce high efficiency NiO and  $\text{WO}_3$  electrochromic films [2], [8]. Techniques like Inkjet printing and self assembly have produced  $\text{WO}_3$  films with higher CE values but with lower optical modulations and higher colour/bleaching times [16], [17]. As shown in table 1.1, although good results have been obtained by solution techniques, the performance of  $\text{WO}_3$  and NiO solution-based films is still lower than the obtained through vacuum based techniques. Therefore, it is highly important to improve the EC performance of solution based  $\text{WO}_3$  and NiO films, helping lower the costs of mass production.

## 1.2 Solution Combustion Synthesis

Solution combustion synthesis (SCS) is a possible alternative method that can help lowering the production costs of NiO and  $\text{WO}_3$  EC films [20], [21], [22]. This method is based on an exothermic redox reaction between a metal precursor and a fuel. The metal precursor will receive electrons from the fuel and the metal oxides will be produced [23]. To trigger the combustion, it is necessary to provide a certain temperature to the precursor solution, (ignition temperature), leading to a strong exothermic reaction. Being a low temperature process, it can be seen has a greener alternative to typical fabrication methods of EC films that evolve higher temperatures, high pressures (hydrothermal synthesis) or vacuum (sputtering) [23].

The final properties of the produced thin films will depend on the reaction parameters like the fuel (reducer), the metal source (oxidizer), the reducer to oxidizer ratio ( $\phi$ ), the initiation type, the ph of the precursor solution and the atmosphere environment [23].



There are some reports of NiO EC films made by SCS [20], [22]. A recent study reported NiO spin coated films made by SCS using nickel nitrate as metal source (oxidizer) and thiourea as fuel (reducer), with good optical modulation, 60% (550 nm), but with low colour efficiency,  $26 \text{ Cm}^2.\text{C}^{-1}$ , and high colouration time, 12s [22].

Similarly to NiO,  $\text{WO}_3$  films have also been produced through SCS [21]. A recent work produced  $\text{WO}_3$  spin coated films with different thicknesses using  $\text{WCl}_6$  as metal source, acetic acid as fuel

and hydrogen peroxide as chelating agent. The best results had an optical modulation of 40% (633 nm), a coloration efficiency of  $35 \text{ cm}^2 \cdot \text{C}^{-1}$  and coloration/bleaching times of 32/10 [21]. In this work SCS was used to produce both  $\text{WO}_3$  and NiO thin films, their properties and application in EC devices were evaluated.

Table 1.1- State of the art of NiO and  $\text{WO}_3$  electrochromic devices.

	Method	Electrolyte	CE ( $\text{Cm}^2 \cdot \text{C}^{-1}$ )	$\Delta T$ (%)	Coloration/ Bleaching Times (s)	Ref
<b><math>\text{WO}_3</math></b>	Sol Gel	1M LiClO <sub>4</sub> -PC	56	56 (633 nm)	6/3	[24]
	Combustion	1 M LiI-PEG	35	40 (633 nm)	32/10	[21]
	Spray Coating	0.2 M LiClO <sub>4</sub> -PC	77	98 (633 nm)	5/4.0	[18]
	Inkjet Printing	61:17:7:15 ACN:PC:LiClO <sub>4</sub> :P MMA	132	75 (633 nm)	10/13	[17]
	Self assembly	0.1M LiClO <sub>4</sub> -PC	121	61 (1060 nm)	86/78	[16]
	Hydrothermal	1M LiClO <sub>4</sub> -PC	57	78 (630 nm)	5/6	[15]
	Solvothermal	1M H <sub>2</sub> SO <sub>4</sub>	75	75 (630 nm)	7/2	[14]
	Sputtering	1M LiClO <sub>4</sub> -PC	81	73 (1000 nm)	5/3	[19]
<b>NiO</b>	Sputtering	1 M PC-LiClO <sub>4</sub>	24	55 (-)	10/4	[13]
	Sol Gel	1 M KOH	71	51 (550 nm)	-	[12]
	Hydrothermal	1 M LiOH	57	70 (600 nm)	5/7	[10]
	Solvothermal	1 M KOH	31	64 (550nm)	12/10	[9]
	Spray Pyrolysis	0.5 M PC-LiClO <sub>4</sub>	31	39 (550 nm)	8/2	[11]
	Combustion	1 M NaOH	26	60 (550 nm)	12/4	[22]
1 M LiClO <sub>4</sub>		92	55 (550 nm)	17/2	[20]	



## MATERIALS AND METHODS

With the aim of understanding the EC performance of combustion based  $\text{WO}_3$  and NiO thin films, precursor solutions of both materials were prepared by SCS and deposited by spin-coating. This process was optimized, and the thin films were properly characterized.

### 2.1 $\text{WO}_3$ and NiO precursor solutions preparation

To prepare the NiO precursor solution, 0.29 g of nickel (II) nitrate,  $\text{Ni}(\text{NO}_3)_2 \cdot 6\text{H}_2\text{O}$ , (Sigma-Aldrich, CAS:13478-00-7) were dissolved in 10 ml of 2-methoxyethanol,  $\text{CH}_3\text{OCH}_2\text{CH}_2\text{OH}$ , (Sigma-Aldrich, CAS:109-86-4) in a concentration of 0.1 M. To complete the exothermic reaction, 0.1 g of urea,  $\text{CH}_4\text{N}_2\text{O}$ , (Fisher Chemical, CAS:57-13-6) was added and the mixture was left stirring. To prepare the  $\text{WO}_3$  precursor solution, 1g of tungsten hexachloride,  $\text{WCl}_6$ , (Sigma-Aldrich, CAS:13283-01-7, >=99.9%) was dissolved in 10 ml ethanol absolute,  $\text{C}_2\text{H}_6\text{O}$ , (Merck, CAS:64-17-5), in a concentration of 0.18 M. Afterwards, 2 ml of acetic acid,  $\text{CH}_3\text{CO}_2\text{H}$ , (Merck, CAS:64-19-7, 99%) was added to the mixture and the solution was left stirring for 30 minutes. To finalize, 2 ml of hydrogen peroxide,  $\text{H}_2\text{O}_2$ , (Panreac AppliChem, CAS:7722-84-1, 30%) was added and the solution was left stirring at 40 °C for 2 hours. The stoichiometric calculations for both reactions are presented in annex A1.

### 2.2 $\text{WO}_3$ and NiO thin films production and characterization

The NiO and  $\text{WO}_3$  precursor solutions were deposited by spin-coating on silicon, glass and ITO/glass substrates to produce the respective thin films. Prior to deposition, all silicon and glass substrates were cleaned in an ultrasonic bath, in acetone, in isopropanol and in water

during 15 minutes each stage, followed by exposure to UV/Ozone in a PSD-UV Novascan system, with a lamp distance of 3 cm.

Immediately after exposure, 8 layers of each film were deposited by spin coating (Laurell). Each deposition had a duration of 35 seconds at 3000 rpm and an acceleration of 2000 rpm, followed by immediate annealing in a hot plate at 300 °C, for 5 minutes between layers and a final annealing step of 1 hour. To allow the necessary access to the conductive ITO contact two methods were used; i) a small region of the ITO/glass was covered with kapton tape prior to the deposition, ii) no tape was used prior to spin-coating and the oxide thin film was exposed after deposition, by chemical etching with HCl (Merck, CAS:7647-01-0, 37%) using kapton tape as a mask to protect the film.

To assist the chemical etching, a study of the annealing time influence in the ITO resistance was performed. For that purpose, one ITO/glass sample was submitted to the same annealing procedure used for the film production and a second sample without the final 1h annealing step. The resistance of the ITO contact was measured with a multimeter.

The film's thickness was measured with a profilometer Ambios XP-Plus 200 Stylus. X-ray measurements were made from 10° to 60° with a Malvern Panalytical Aeris to understand the crystallographic structure of the films, while SEM analysis was made with a SEM Hitachi Regulus SU8220 to understand their crystallographic structure.

FTIR-ATR analysis was made with the Si samples in order to understand if there was a complete conversion to metal oxide.

To study the transmittance of the films, spectrophotometer, (Perkin Elmer lambda 950 UV-VIS-NIR), measurements were made from 200 nm to 800 nm, in the original, coloured and bleaching states. The coloured and bleaching states were obtained by applying voltages with a potentiostat (Gamry Ref 600). The same system was used to obtain cyclic voltammetry curves, applying voltages between -1 V and 1.5 V for NiO films and -1.5V and 1 V for WO<sub>3</sub>, with a scan rate of 50 mV.s<sup>-1</sup>. Chronoamperometry measurements were also made, with the help of an Ocean Optics portable spectrophotometer, to extract the ON-OFF cycles, by applying voltages of -0.5V and 1 V during 90s each for NiO and of -0.5 and -0.25 for the same period for WO<sub>3</sub> films.

To perform the electrical measurements as well as to achieve the coloured and bleaching states, a LiClO<sub>4</sub> electrolyte, (C=0.1M), was in contact with a platinum counter electrode and a reference electrode (Ag/AgCl). To prepare the electrolyte, lithium perchlorate, LiClO<sub>4</sub>, (Sigma Aldrich, CAS: 7791-03-9, >=98%), was added to Propylene Carbonate, C<sub>4</sub>H<sub>6</sub>O<sub>3</sub>, (Acros Organics, CAS: 108-32-7, >95%) and left stirring until it was completely dissolved.

## RESULTS AND DISCUSSION

The obtained results are presented in the following chapter. Firstly, it is presented the difference between the devices produced with kapton tape during spin coating and the devices where the ITO contact was produced through chemical etching. Secondly, the characterization results of the optimized films are exposed and discussed.

### 3.1 NiO and WO<sub>3</sub> solution preparation and film deposition

A brief resume of the steps followed to produce the NiO and WO<sub>3</sub> precursor solutions and EC films is presented in figure 3.1.

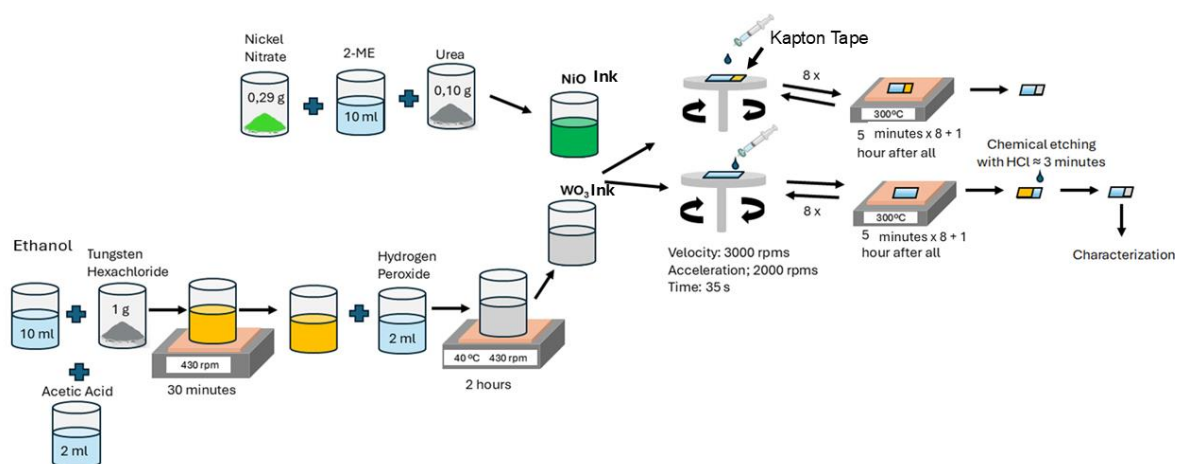


Figure 3.1- Schematic of the steps followed for NiO and WO<sub>3</sub> EC film production

In order to colour/bleach the device, it was essential to maintain an ITO contact that could allow the application of a voltage and lead to ion insertion/extraction. To preserve an ITO region, during spin coating, kapton tape was used, in an initial phase. Figure 3.2 presents the

final outlook of the a) NiO and c) WO<sub>3</sub> films produced with kapton tape. Since kapton tape has hydrophobic properties, the solution presented a natural tendency to move away from the tape during the deposition process, leading to non-uniform films. This effect is more visible in the NiO films, where the region opposite to the ITO contact has a small uniform area. This problem was overcome by making the deposition without protecting the ITO contact with kapton tape and carrying out chemical etching with HCl afterwards. The approximate etching time for both films was around 3 minutes, depending on the age and concentration of the HCl solution. Figure 3.2 shows the optimized b) NiO and d) WO<sub>3</sub> films. Comparing these films with the films produced with kapton tape during spin coating, there is a clear improvement in their uniformity. From figure 3 d) It is also possible to observe that there was some material accumulation at the borders of WO<sub>3</sub> films due to the spin-coating process.

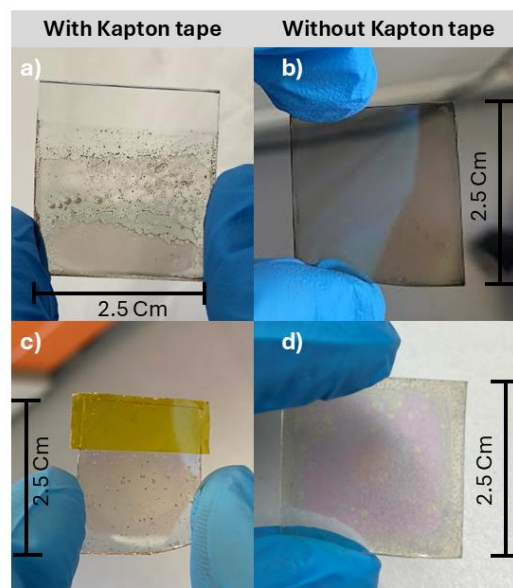


Figure 3.2- Final aspect of NiO and WO<sub>3</sub> thin films produced with (a,c) and without (b,d) kapton tape, respectively.

The main concern during chemical etching was to obtain resistance values as close as possible to the ITO resistance, as the contact should be conductive enough to allow insertion/extraction of charges. In order to understand if the obtained values were close to the ITO resistance, it was performed a study of the influence of annealing time in the ITO resistance (Figure 3.3). As expected, the ITO resistance increased with annealing time, (temperature 300 °C). Initially the ITO resistance was  $(25 \pm 2) \Omega$ , after 8 stages of 5 minutes of annealing increased to  $(73 \pm 8) \Omega$

and the sample that remained the same time as the films, 1 hour after the 8 stages of 5 minutes, had an even higher value,  $(125 \pm 28) \Omega$ . For each condition 1 sample was measured.

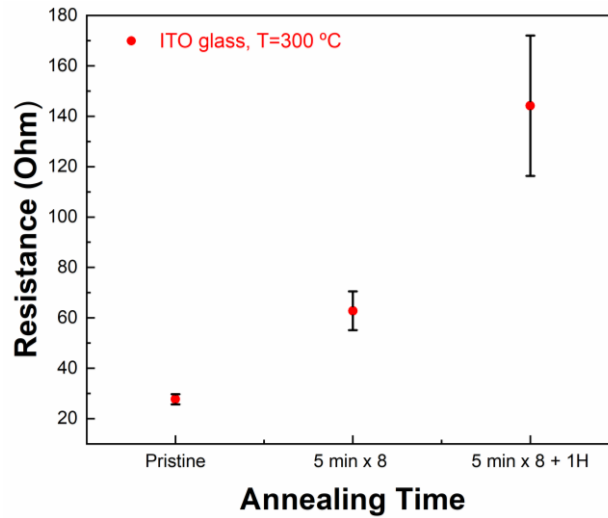


Figure 3.3- Variation of ITO resistance with annealing time

On average the obtained resistance values for the ITO contact after etching,  $(111 \pm 51) \Omega$  for NiO and for  $\text{WO}_3$   $(116 \pm 38) \Omega$ , were slightly lower to the obtained values for the ITO sample that went through the same annealing time,  $(125 \pm 28) \Omega$ , (Figure 3.4). The error bars cover a significant range of values with orders of magnitude that go from the dozens to the hundreds, which might be explained by the quality of the obtained ITO contacts. In most samples there were significant resistance variations trough the contact, the resistance was not the same in different areas possibly due to the presence of some remains of the EC film. Therefore, chemical etching was not uniform trough all ITO contact area. In some samples chemical etching even removed small portions of the ITO, while preserving other regions of the contact. Dry etching is a possible solution to overcome this problem.

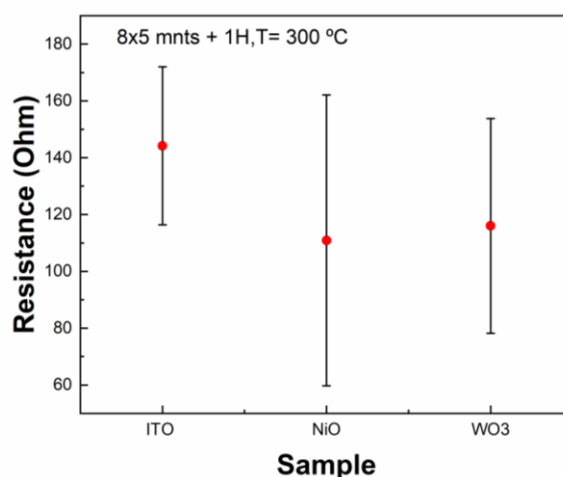


Figure 3.4- Obtained ITO resistance after NiO, WO<sub>3</sub> thin films etching and in ITO glass submitted to the same annealing time.

## 3.2 NiO and WO<sub>3</sub> thin film characterization

The characterization results of the optimized films are presented below as well as a brief discussion. Characterization included profilometry, X-ray diffraction, SEM, FTIR-ATR and UV-Vis-NIR spectroscopy. Lastly, electrochemical characterization included cyclic voltammetry and chronoamperometry measurements, which were made using a potentiostat.

### 3.2.1 Thickness

The thickness of the EC films was measured with a profilometer and plays an important role on the device's efficiency. The material properties of WO<sub>3</sub> and NiO films vary with film thickness, having impact on their EC performance [21], [26]. NiO thin films presented a thickness of (195±6) nm, much higher than the, (53±3) nm obtained for WO<sub>3</sub>, (from an average of 3 samples). Once the spin coater velocity and acceleration were the same for both films, this result can be explained by the different concentration and composition of the precursor solutions. Profilometer measurements also allowed to understand the profile of the interface between the EC films and the ITO contact. Figure 3.5 presents an example of the profilometer profiles obtained for a) NiO and b) WO<sub>3</sub> films. Both films presented high roughness, which enhances their electrochemical performance but, together with the small thickness of WO<sub>3</sub>, made it difficult to measure its value through this technique. AFM measurements should be made to further understand the roughness of the films. Figure 3.5 b) shows a small well at the interface

between the  $\text{WO}_3$  film and the ITO contact. In some samples, non-uniform etching led to this situation, preserving the ITO contact while etching the ITO at the interface, damaging the device. These results show a need to further study and improve the NiO and  $\text{WO}_3$  film's etching to allow for reproducible devices.

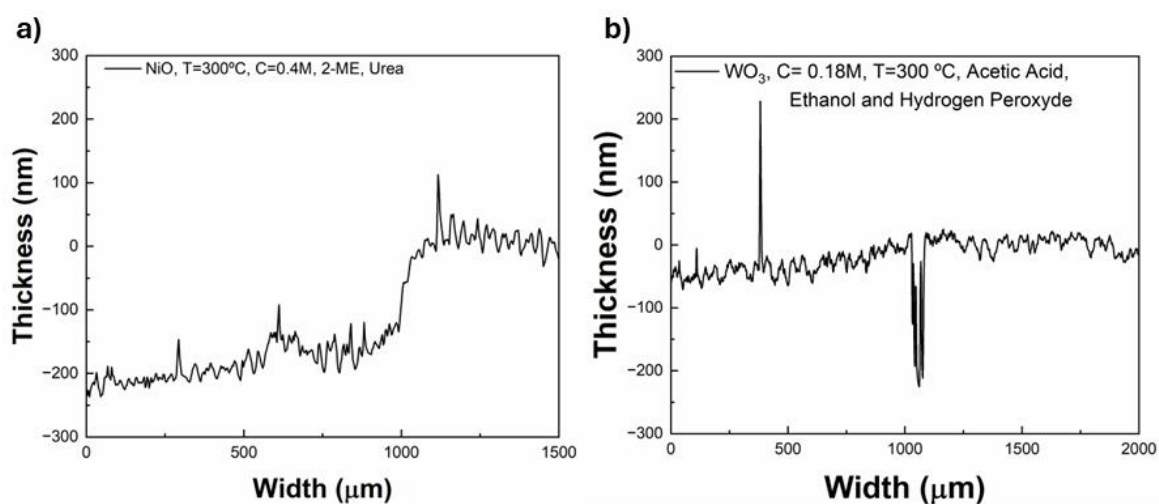


Figure 3.5- Profilometer profiles of a) NiO and b)  $\text{WO}_3$  thin films.

### 3.2.2 X-ray diffraction (XRD)

The crystallographic structure of an EC film has a big influence on its efficiency. Crystalline films have better cyclic stability and better adhesion to the substrate, while amorphous have enhanced switching times and higher coloration efficiencies [2]. The obtained diffractograms are presented in figure 3.6. Both diffractograms revealed the presence of broad bands, rather than the typical sharp peaks of crystalline materials, revealing a short range order for both films. This results are in accordance with a study where  $\text{WO}_3$  EC films with different thicknesses were produced by SCS and deposited by spin coating [21]. Samples with less than 150 nm were found to be amorphous, while thicker films presented a polycrystalline structure [21]. The same crystallinity modification with thickness increase has been reported for NiO thin films produced by electron beam evaporation [25]. Therefore, a possible path to increase the crystallinity of the  $\text{WO}_3$  films could be by producing samples with thicknesses higher than 150 nm. This could be done by increasing the concentration of the precursor solution or increasing the number of deposited layers. Increasing the concentration of the  $\text{WO}_3$  precursor solution trough the same protocol of this work can be challenging, as the reaction is highly exothermic and unstable.

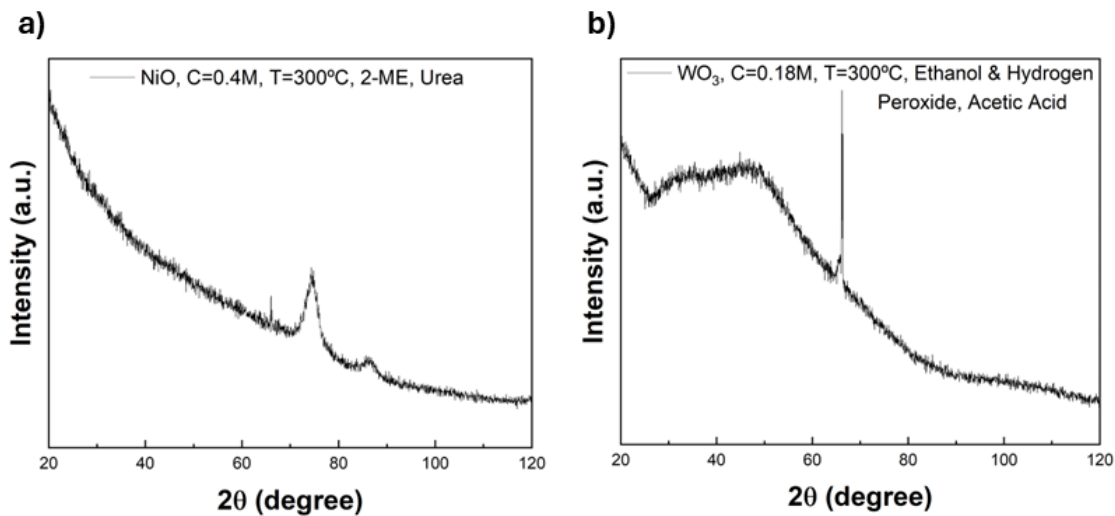


Figure 3.6- X-Ray diffractograms of a) NiO and b) WO<sub>3</sub> films.

### 3.2.3 Scanning Electron Microscopy (SEM)

As shown in figure 3.7 b), SEM analysis revealed the high porosity of the NiO films. Porous films have an increased contact area between the film and the electrolyte, decreasing the diffusion path of the ions. This will facilitate the charge transfer and, will, therefore, improve the EC properties of the film [2], [8].

SEM images of the NiO films also allowed to verify the absence of cracks on the structure. EDS analysis can be made in the future to understand the composition of the films and verify if NiO is the only element present in the structure.

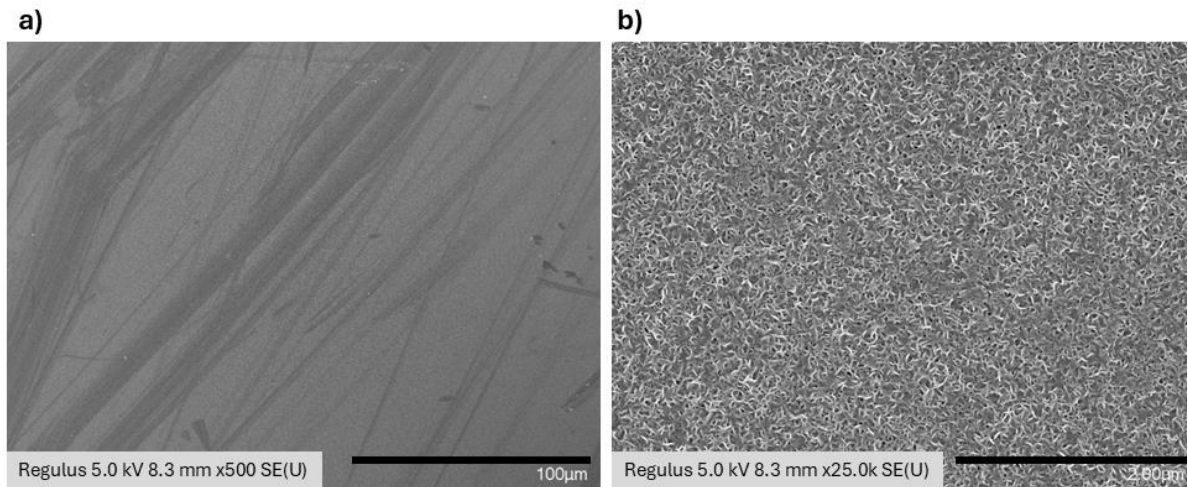


Figure 3.7- SEM Images of NiO films for a magnification of a) x500 and b) x25.0k.

The obtained SEM images of the  $WO_3$  films are presented in figure 3.8 and revealed they did not present any kind of porous structure. The observable white dots can be related to the Au previously deposited to carry the SEM measurements. This result is similar to the previously mentioned report where  $WO_3$  thin films produced by SCS and deposited by spin coating did not present a porous structure [21]. SEM images also show the absence of cracks, which are often reported for  $WO_3$  films that undergo annealing treatments due to the strain imposed by this process [21].

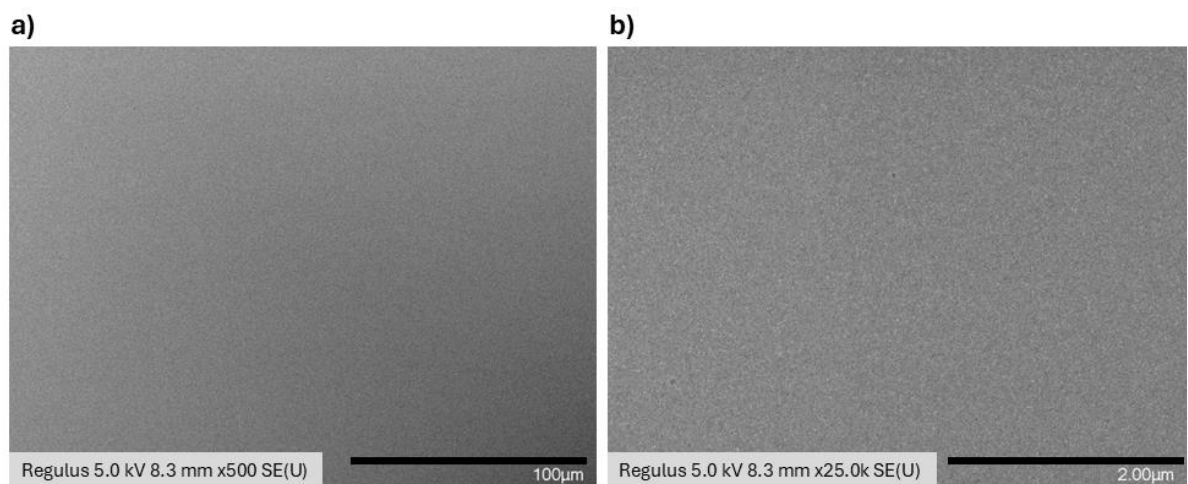


Figure 3.8- SEM Images of  $WO_3$  films for a magnification of a) x500, b)25.0k.

### 3.2.4 Fourier Transform infrared spectroscopy (FTIR-ATR)

Figure 3.9 shows the obtained FTIR-ATR spectra for both a) NiO and b) WO<sub>3</sub> films deposited in a silicon substrate for samples submitted to the 8 annealing stages of 5 minutes with and without the final 1 hour step. NiO films that were not submitted to the final 1 hour step presented peaks in the hydroxyl region (3432-3672) cm<sup>-1</sup> (peak 1), and in the nitrate region, (1200-1500) cm<sup>-1</sup> (peak 2) [26],[27]. The NiO spectra of the films that went through the 1 hour annealing stage did not present this peaks, revealing the importance of this step to convert the metal oxide. The obtained spectra for WO<sub>3</sub> films (figure 3.9 a)) did not present any significant peaks for both conditions, therefore the 8 annealing stages of 5 minutes between layers are enough to convert the metal oxide and the final 1 hour annealing is not relevant to convert to the process.

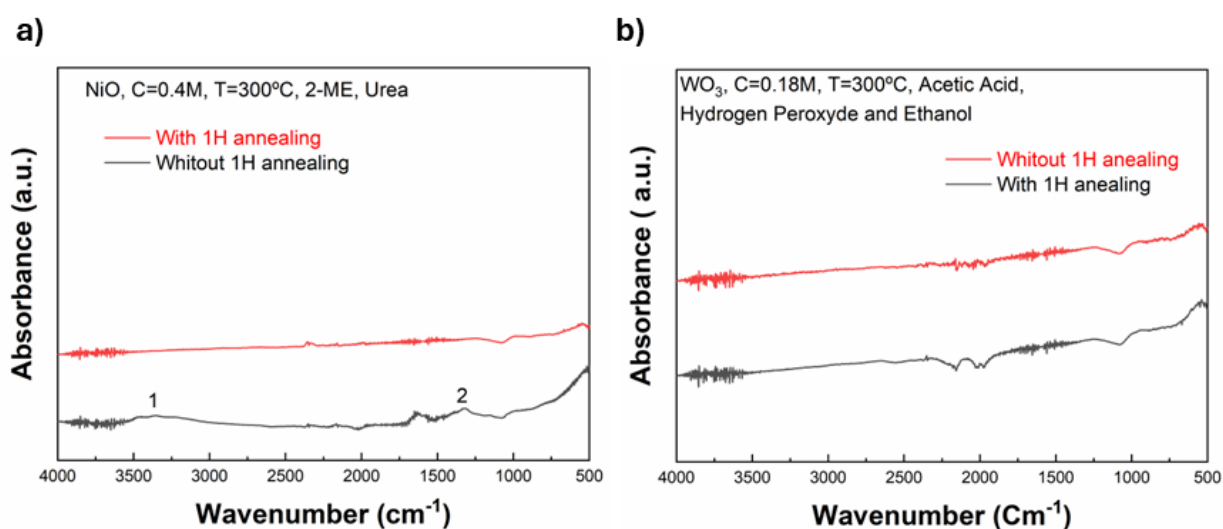


Figure 3.9- FTIR-ATR spectra of a) NiO and b) WO<sub>3</sub> films.

### 3.2.5 UV-Visible Spectroscopy

Transmittance measurements of the as deposited films on a glass substrate revealed the high transparency of the films, as shown in Figure 3.10. WO<sub>3</sub> films presented a transmittance of 80% (average between 550 nm and 633 nm), while NiO presented a lower value, 65% (average between 550 nm and 633 nm). Most optical modulation values are reported for 550 nm or 633 nm, an average between these values allowed to cover more wavelengths of the visible spectrum.

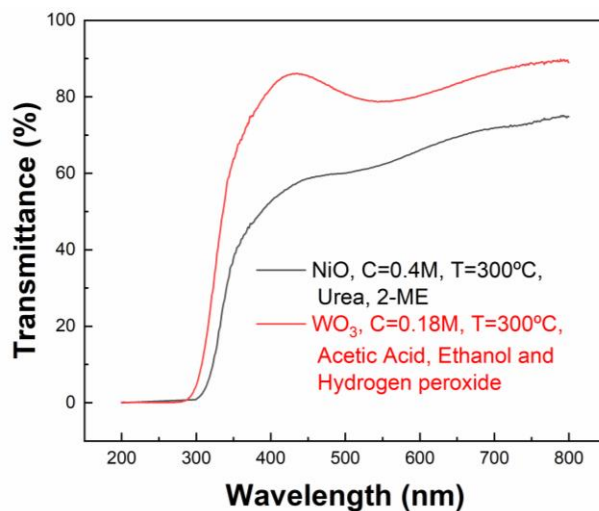


Figure 3.10- Transmittance of NiO and WO<sub>3</sub> thin films on a glass substrate.

To demonstrate the devices performance, voltages of 1 V and -1 V were applied to the ITO contacts of the NiO and WO<sub>3</sub> thin films immersed in the LiClO<sub>4</sub> electrolyte. Figure 3.11 presents the obtained spectra from 200 nm to 800 nm for both films in the initial, coloration and bleaching states. From figure 3.11 a) it can be seen that NiO films presented higher transparency after bleaching than at the initial state, and an optical modulation of 20 % ,(average between 550 nm and 633 nm). The reason behind this effect on the NiO films might be related with ion insertion/extraction during the fabrication process that could have led to some intermediate coloration between bleach and coloured states. The optical modulation of NiO films was considerably lower than a recent report of SCS of NiO thin films that used 1 M NaOH as electrolyte, obtaining an optical modulation of 60% (550 nm) [22]. On the other hand, while the annealing stage of this report was made for 3 hours at 450 °C, in this work annealing was made at a lower temperature, 300 °C for 8 x 5 minutes between layers and one hour after all.

In figure 3.11 b) it can be seen that, unlike NiO, WO<sub>3</sub> films were more transparent at the initial state than after bleaching and had an optical modulation of 20%, (average between 550 nm and 633 nm). It is interesting to compare the obtained results with a recent study where EC WO<sub>3</sub> spin coated thin films produced by SCS with a thickness of 113 nm and an identical optical modulation of 25% [21]. Once the optical modulation is similar and the thickness is much higher, films produced in this work are more efficient that the reported in the study.

The produced WO<sub>3</sub> films also presented memory effect. After bleaching, it was possible to visually observe the device did not change completely but presented a slightly blue tone (figure 3.13). This effect is common in WO<sub>3</sub> films and can be explain by ion trapping at the films

structure [8]. There are reports of  $\text{WO}_3$  films produced at low annealing temperatures leading to the loss of  $\text{W}=\text{O}$  and  $\text{W}-\text{O}$  bonds and creating trapping sites for  $\text{Li}^+$  ions [8]. A stronger discoloration voltage could help overcome this problem, but it could also damage the thin film [8].

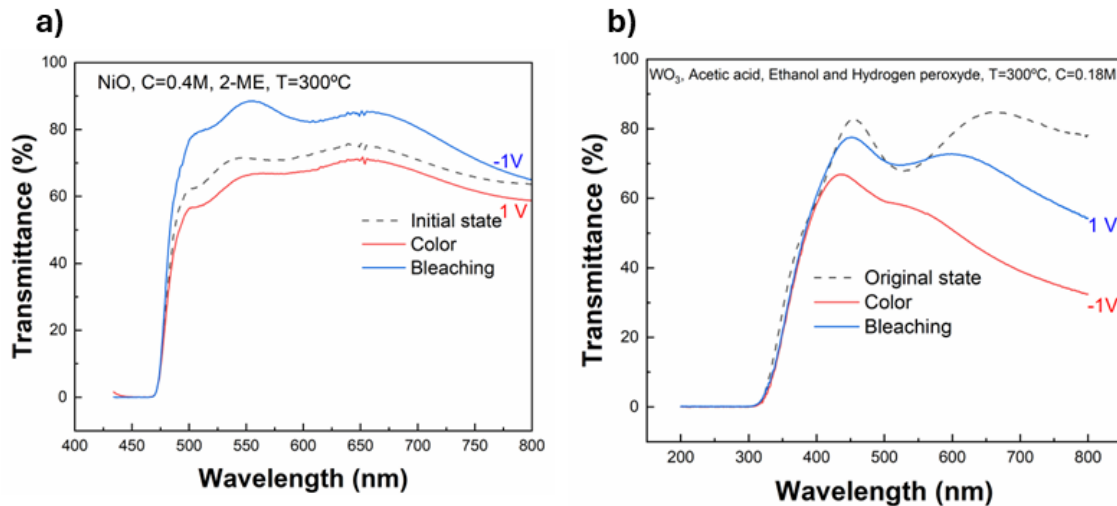


Figure 3.11- Transmittance at initial, coloured and bleached state for a) NiO and b)  $\text{WO}_3$  films, for voltages of  $\pm 1\text{V}$ . The measurements were performed with a  $\text{LiClO}_4$  electrolyte ( $C=0.1\text{M}$ ), a platinum counter electrode and a reference electrode.

Figure 3.12 presents the final outlook of the NiO devices produced with kapton tape and through chemical etching. Both coloration and bleaching states were more uniform for the films where the ITO contact was produced through chemical etching, showing a clear improvement in the cells performance.

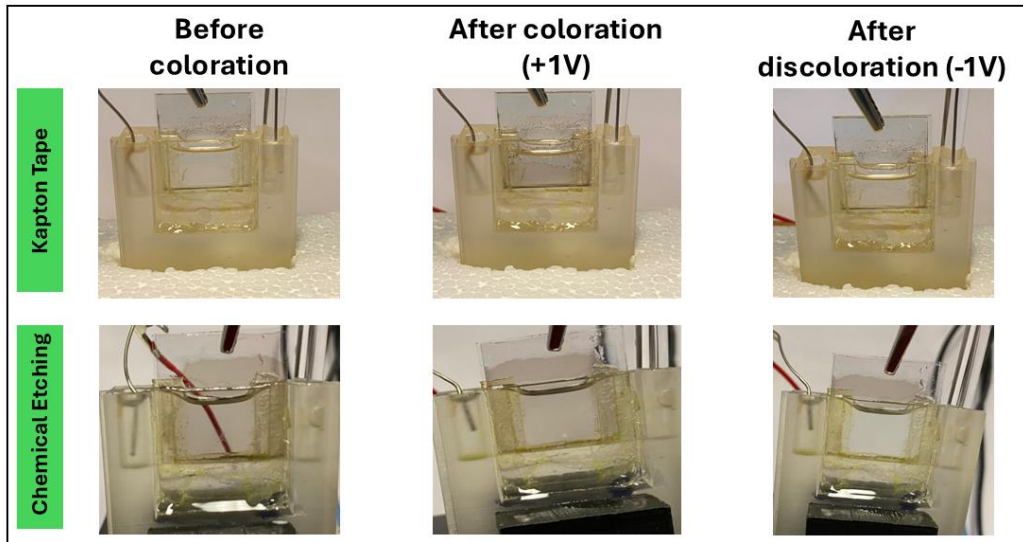


Figure 3.12- Final outlook of NiO films before coloration, after coloration and after discoloration for  $\pm 1V$ .

Figure 3.13 presents the final aspect of the  $WO_3$  devices produced with kapton tape and through chemical etching. Both films presented memory effect after discoloration, but films produced through chemical etching presented more uniform coloration and bleaching states. An  $LiClO_4$  electrolyte with a concentration of  $C=0.5M$  was also tested, but it damaged the film.

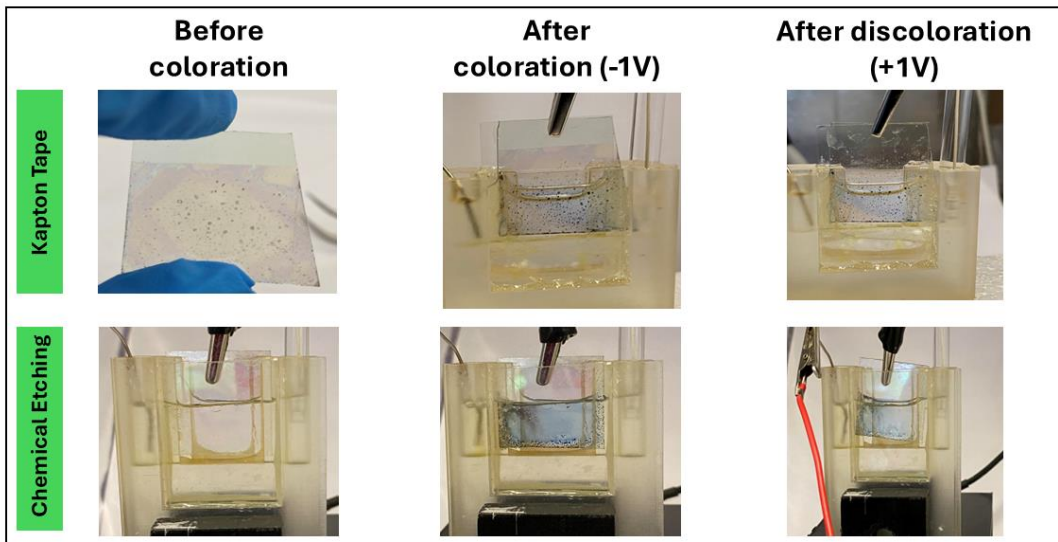


Figure 3.13- Final outlook of  $WO_3$  films before coloration, after coloration and after discoloration for  $\pm 1V$ .

To colour/bleach the devices, as well as to perform the cyclic voltammetry measurements a set up similar to figure 3.14 was used without the portable spectrophotometer, the optical fibers and the light source. The transmittance curves presented in this chapter were measured in a spectrophotometer apart from the set up. The portable spectrophotometer, the optical fibers

and the light source presented in figure 3.14 were used for chronoamperometry measurements.

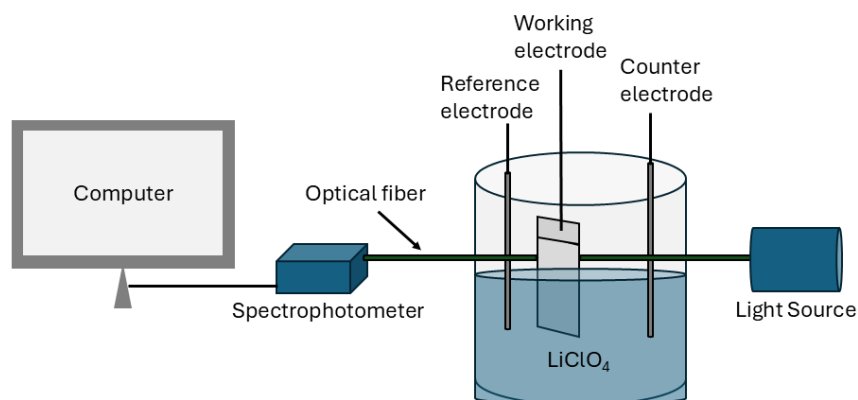


Figure 3.14- Set up used to perform electrochemical measurements. A platinum counter electrode and a LiClO<sub>4</sub> electrolyte were used. The electrodes were connected to a potentiostat.

### 3.2.6 Cyclic Voltammetry

Cyclic Voltammetry is important to understand the cycling stability of the electrochromic films. Figure 3.15 presents the cyclic voltammograms for the first ten cycles for both a) NiO and b) WO<sub>3</sub> films. NiO curves presented two cathodic peaks, 0.4V (I); 0.1mA, 0.9V; 0.16 mA (II) and two anodic peaks, 0.1V;-0.15 mA (I), 0.7V;-0.1 mA (II), therefore having two oxidation states and two reduction states, as depicted in Figure 3.15 a). A recent study has reported similar results for NiO solution based EC films, with two cathodic peaks, 0.3V, 0.9V and two anodic peaks, 0.0V, 0.5V but with double current density [20]. The appearance of two oxidation and two reduction states is typical of NiO films in non aqueous electrolytes like LiClO<sub>4</sub>, and is explained by the double injection and extraction of charges [2].

As the cycles draw near the 10<sup>th</sup>, the current increases and tends to stabilize. Therefore, since the area under the CV curves represents the charge storage capacity of the films, the EC behaviour increase as the cycle draw near the 10<sup>th</sup> due to an increased capacity to store charges. This phenomenon could be explained as an activation step, being a typical behaviour of NiO devices with aqueous electrolytes [2]. There are reports of a significant increase of charge capacity that can last the first hundred cycles [2]. This behaviour did not occur with WO<sub>3</sub> thin films as their peak current density remained stable trough the cycles.

WO<sub>3</sub> curves only presented one cathodic peak at 0.1V, 0.6mA (I) as shown in Figure 3.15 b). Once the coloration/bleaching mechanism is based on a redox process, a cathodic peak was expected to appear, completing the redox cycle. If the cycles covered more negative values, surpassing -1.5 V, the cathodic peak would appear, but once the device could get damaged,

higher voltages where not explored. During the bleaching process,  $\text{WO}_3$  films presented a current of 0.49 mA, more than the double of NiO 0.15 mA, meaning more charges were injected into the  $\text{WO}_3$  when compared with NiO thin films.

The obtained  $\text{WO}_3$  cycles match the results of an already mentioned study where  $\text{WO}_3$  films with thicknesses from 41 nm to 750 nm were produced trough SCS [21]. For 41 nm films, the study reported an anodic peak current of 0.20 mA, against 0.26 mA of this work, where the films had 53 nm [21]. Therefore, this work was able to obtain a similar current with a slightly higher thickness.

The area under the curves of NiO is bigger than under the  $\text{WO}_3$ , consequently NiO films have more capacity to store charges than  $\text{WO}_3$ , leading to a higher efficiency, this can be explained by the higher porosity of the NiO devices.

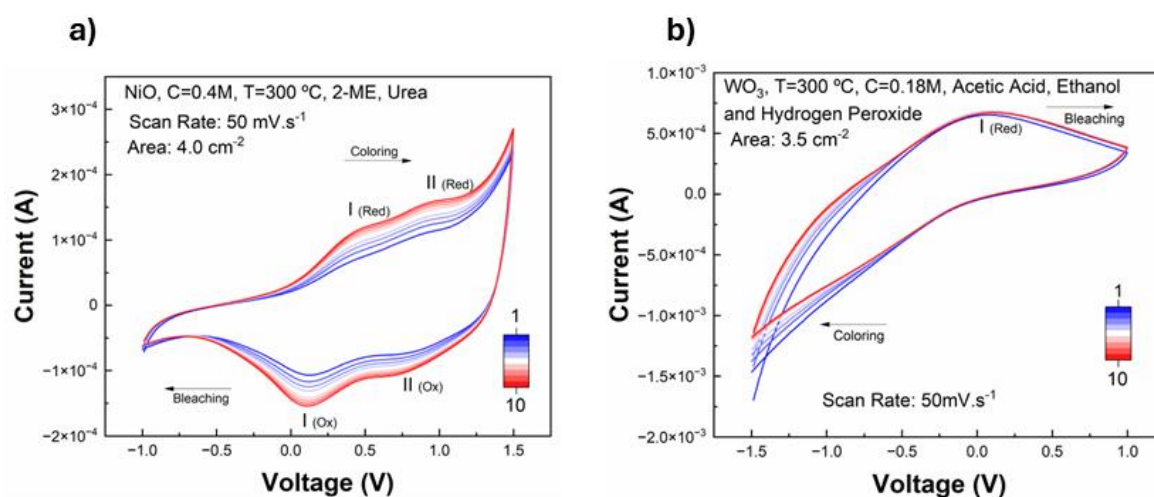


Figure 3.15- First 10 cyclic voltammety cycles for a) NiO and b)  $\text{WO}_3$  cells. The measurements were made with a  $\text{LiClO}_4$  electrolyte and a platine counter electrode.

### 3.2.7 Chronoamperometry

Chronoamperometry curves allowed to calculate the coloration/bleaching times of the films as well as to understand the optical modulation variation trough the coloration/bleaching cycles. Figure 3.16 a) presents the obtained results for NiO films during 15 cycles. The applied coloration/bleaching voltages were 1V/-0.5V respectively. As shown in figure 3.16 b), transmittance in both coloured and bleached states increased until the 5<sup>th</sup> cycle, when it stabilizes. Through this process the optical modulation remains practically the same. This might be explained by the same activation step that led to an increase of current and prior stabilization during cyclic voltammety. Coloration/Bleaching times are defined as the necessary time for a 90%

coloration/bleaching variation to occur [6]. These times were extracted from the final 5 cycles, (figure 3.16 b)) since the curves were more stable. NiO films presented a coloration time ( $t_{c,90\%}$ ) of  $(21 \pm 1)$  s and a bleaching time of ( $t_{b,90\%}$ )  $(8 \pm 1)$  s. A recent study reported coloration/bleaching times of 17/2s, although the obtained results did not surpass these times, they are still acceptable for EC windows [20]. The protocol followed by the study evolved a 24 hours drying stage followed by annealing at 230 °C for 90 minutes while this work only had 8 stages of 5 minutes between layers and one hour after hall [20].

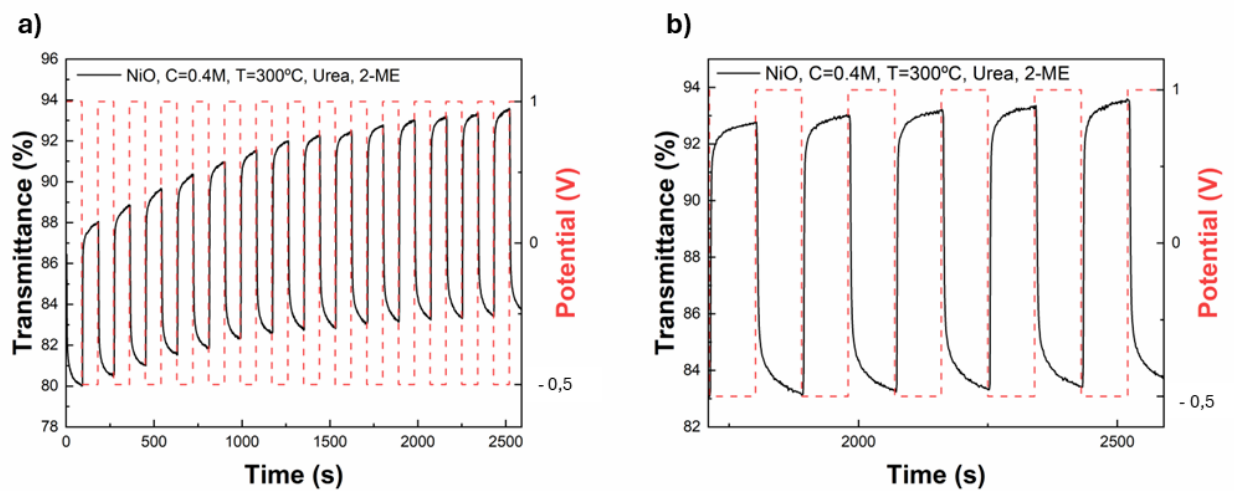


Figure 3.16- Chronoamperometry measurements of anodic NiO cells for a) the first 15 cycles, b) the final 5 cycles.

Figure 3.17 a) presents the chronoamperometry results for  $WO_3$  films for the first 15 cycles, where voltages of -1.5 V and -0.25 V were applied for coloration/bleaching. While optical modulation remains constant, the transmittance in both colour and bleach state decreased continuously until the 10<sup>th</sup> cycle, where it stabilized. A possible cause can be the previously mentioned capture of electrolyte  $Li^+$  ions by the film structure that leads to an Irreversible colour change [8]. This phenomenon has been appointed as the main degradation reason of the EC performance for  $WO_3$  devices[8]. Potentiostatic conditioning of the films has been indentified has a possible technique to improve the reversibility of the coloration/bleaching process, improving the performance of the films affected by this problem [8]. Similarly to NiO, coloration/bleaching times for  $WO_3$  films were calculated for the final 5 cycles (figure 3.17 b)), where the curves were more stable.  $WO_3$  films presented a coloration time ( $t_{c,90\%}$ ) of  $(45 \pm 7)$  s and a bleaching time ( $t_{b,90\%}$ ) of  $(46 \pm 4)$  s. Recent studies of  $WO_3$  solution based spin coated EC films reported lower

coloration/bleaching times of 20s/5s for films with 113nm thickness or even 36s/13s for films with 456 nm of thickness [21]. Another study reported the production of  $\text{WO}_3$  films by self-assembly with coloration/bleaching times of 86 s/78 s, which are much higher than the  $(45 \pm 7)$  s/ $(46 \pm 4)$  s obtained in this work [16]. Comparing  $\text{WO}_3$  and NiO switching times, even with a higher thickness, NiO films ( $(195 \pm 6)$  nm) take less time to colour/bleach  $(21 \pm 1)$  s/ $(8 \pm 1)$  s than  $\text{WO}_3$  ( $(53 \pm 3)$  nm),  $(45 \pm 7)$  s/ $(46 \pm 4)$  s.

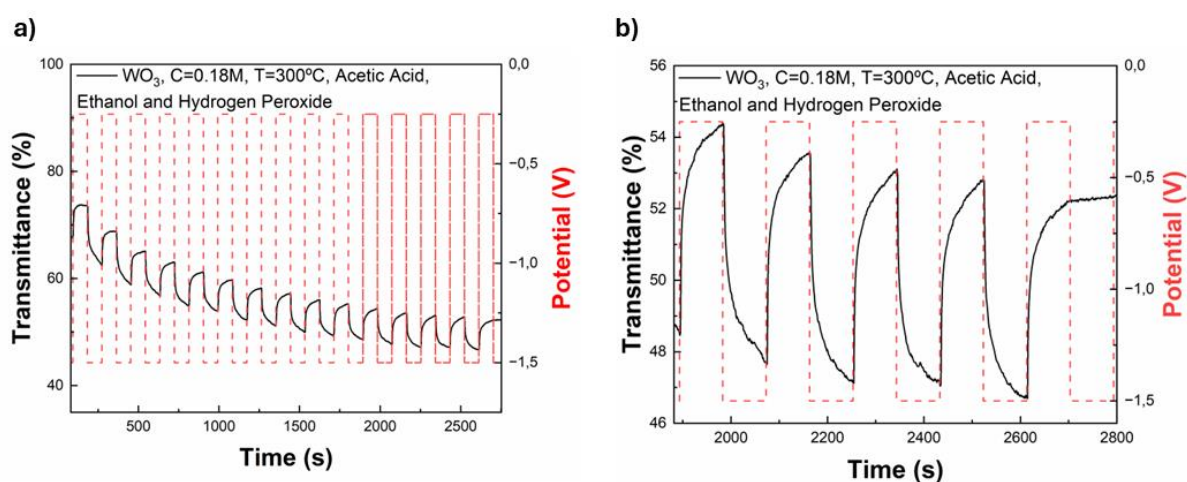


Figure 3.17- Chronoamperometry measurements of cathodic  $\text{WO}_3$  cells for a) the first 15 cycles b) the final 5 cycles.

The optical modulation values obtained with chronoamperometry measurements did not match the ones obtained when testing the device's performance, (where the transmittance was measured in a separate spectrophotometer). This effect might be explained by the setup of the chronoamperometry measurements, therefore the values presented in figure 3.11 are more reliable and were used to compare with the reported literature. Nevertheless, these results allowed to verify that there were reversible coloration/bleaching cycles as well as to calculate the coloration/bleaching times.

Table 3.1 presents the state of the art for NiO and  $\text{WO}_3$  solution based EC devices, as well as the results obtained in this work.

Although the EC properties of the produced NiO and  $\text{WO}_3$  films were lower than most results reported in literature, this work reached acceptable properties for application in EC devices through a simpler and low-cost method.

Table 3.1- Comparison between state of the art of solution-based NiO and WO<sub>3</sub> EC devices and the results obtained in this work

	Method/ Structure	Electrolyte	CE (Cm <sup>2</sup> .C <sup>-1</sup> )	$\Delta T$ (%)	Coloration/ Bleaching Times (s)	Ref
<b>WO<sub>3</sub></b>	Combustion	1M LiClO <sub>4</sub> -PC	56	556 (633 nm)	6/3	[24]
		1 M LiI-PEG	35	40 (633 nm)	32/10	[25]
	Spray Coating	0.2 M LiClO <sub>4</sub> -PC	77	98 (633 nm)	5/4	[18]
	Inkjet Printing	61:17:7:15 ACN:PC:LiClO <sub>4</sub> :P MMA	132	75 (633 nm)	10/13	[17]
	Self assembly	0.1M LiClO <sub>4</sub> -PC	121	61.4 (1060 nm)	86/78	[16]
	<b>This Work</b>	0.1 M LiClO <sub>4</sub>	-	20 (550- 633) nm	45/46	-
<b>NiO</b>	Sol Gel	1 M KOH	71	51 (550 nm)	-	[12]
	Spray Pyrolysis	0.5 M PC-LiClO <sub>4</sub>	31	39 (550 nm)	8/2	[11]
	Combustion	1 M NaOH	26	60 (550 nm)	11.8/4	[22]
		1 M LiClO <sub>4</sub>	92	55 (550 nm)	17/2	[20]
	<b>This Work</b>	0.1 M LiClO <sub>4</sub>	-	20 (550- 633) nm	21/8	-

Once both films presented a reversible electrochromic behaviour, it would be interesting to combine them in a complementary effect electrochromic window. Voltages between -1V and 1V could be tested, once they did not damaged the devices produced in this work.

## CONCLUSION AND FUTURE PERSPECTIVES

The objective of this work was to produce and characterize solution combustion synthesis based NiO and WO<sub>3</sub> EC films deposited by spin coating. The first spin coating depositions were made with a small region of the ITO glass covered with kapton tape to preserve a contact conductive enough to allow charge insertion/extraction. The metal oxide thin films produced through this method were not uniform and a second production method was explored by making the deposition without the tape and proceeding with HCl chemical etching afterwards. To assist the chemical etching, a study of the influence of annealing time in the ITO resistance was performed. It was observed a resistance increase with the annealing time, from (25±2) Ω, prior to the process, to (125±28) Ω, after 8 stages of 5 minutes plus 1 hour.

Optimized NiO and WO<sub>3</sub> thin films were structurally, optically and electrochemically characterized. X-ray diffraction analysis revealed the lack of long-range order in both films, while SEM analysis disclosed NiO films were porous and WO<sub>3</sub> films were not. NiO films presented higher thickness, (195±6) nm, than WO<sub>3</sub>, (53±3) nm, and an identical optical modulation of 20%. However, these values are lower than most results reported in the literature. For NiO films, Cyclic voltammetry showed that as the cycles draw near the 10<sup>th</sup>, the injected current increased and tended to stabilize. NiO films presented two cathodic peaks at 0.4V (I); 0.1mA, 0.9V; 0.16 mA (II) and two anodic peaks at 0.1V;-0.15 mA (I), 0.7V;0.1 mA (II). While WO<sub>3</sub> films only presented one cathodic peak at 0.1V, 0.6mA (I). Although the obtained peak currents were lower than most results reported in the literature, it was achieved a reversible EC behaviour, for both films. Chronoamperometry measurements allowed to calculate the coloration/bleaching times. NiO films presented coloration/bleaching times of (21±1) s/(8±1) s and WO<sub>3</sub> of (45±7) s/(46±4). These times are higher than most literature reports, but are acceptable for application in EC windows.

Although the electrochromic performance of the produced films was lower than most solution-based NiO and WO<sub>3</sub> EC devices reported in literature, this work was able to produce NiO and WO<sub>3</sub> films with reversible EC performance through a number of cycles, by a simple protocol. To continue this work, chronoamperometry measurements could be made until the 1000<sup>th</sup> cycle to further understand the lifecycle of both films. A possible path to enhance the performance of the WO<sub>3</sub> EC films presented in this work could be to increase their thickness. Another relevant path to follow could also be to reproduce the obtained results with a solid electrolyte, once it would overcome the leakage problem of liquid electrolytes. Finally, since both films presented the ability to colour/bleach at similar voltages, both films could be combined in a complementary effect electrochromic window.

To conclude, SCS proved to be a simple method capable of producing reversible EC films, therefore it is important to continue this work once it can help lowering the production costs of NiO and WO<sub>3</sub> EC devices.

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## ANNEXES

## A.1 Stoichiometric calculations

The stoichiometric calculations made to find the stoichiometry of the two redox reactions that led to the formation of NiO and WO<sub>3</sub> are presented below. Table A1 presents the valence calculations for each reagent. Propellant chemistry determines a valence of +4 for carbon, +1 for hydrogen, 0 for nitrogen, -2 for oxygen [28].

Table A1- Calculation of the valence of the reagents according to propellant chemistry.

Reagent	Chemical Formula	Calculation	Total
OV	$Ni(NO_3)_2 \cdot 6H_2O$	$2 + 2 \times (0 + 3 \times (-2))$	-10
	$H_2O_2$	$2 + 2 \times (-2)$	-2
RV	$CO(NH_2)_2$	$4 + (-2) + 2 \times (0 + 2 \times 1)$	6
	$CH_3COOH$	$4 + 3 \times 1 + 4 + 2 \times (-2) + 1$	8

The molar stoichiometry required to achieve a stoichiometric redox reaction ( $\Phi=1$ ) is obtained by dividing the oxidising and the reducing valences, as shown in table A2.

Table A2-Molar stoichiometry of reagents for  $\Phi=1$

Metal Source	Fuel	$\Phi$	n
Nickel Nitrate	Urea	1	$\frac{5}{3}$
Hydrogen peroxide	Acetic Acid	1	$\frac{1}{4}$

Table A3 presents the chemical equations with the calculated stoichiometry.

Table A3- Redox reactions with the stoichiometry.

Metal Source	Fuel	Solvent	Reaction
Nickel Nitrate	Urea	2-ME	$3Ni(NO_3)_2 \cdot 6H_2O + 5CO(NH_2)_2 \xrightarrow{\Delta T} 3NiO + 8N_2 + 28H_2O + 5CO_2$
Tungsten Hexachloride	Acetic Acid	Ethanol and Hydrogen Peroxide	$WCl_6 + CH_3COOH + 4H_2O_2 \xrightarrow{\Delta T} WO_3 + 6HCl + 4H_2O + 2CO_2$





2024

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Solution-processed oxide thin films for electrochromic de-vices application